



# **EE 232 Lightwave Devices**

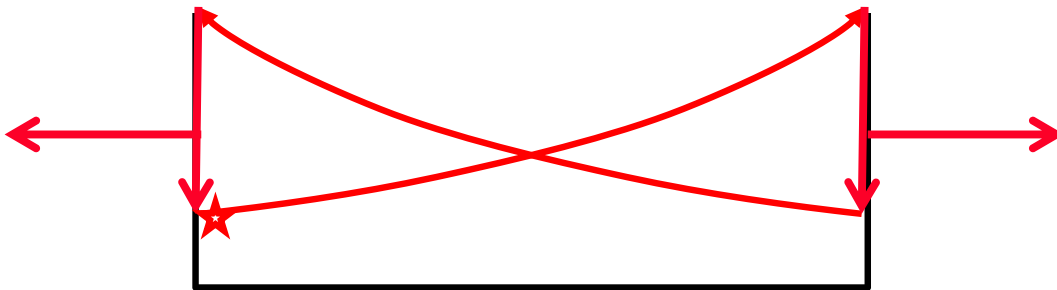
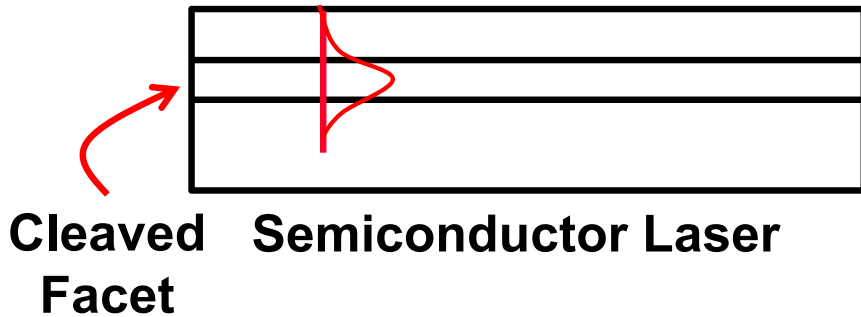
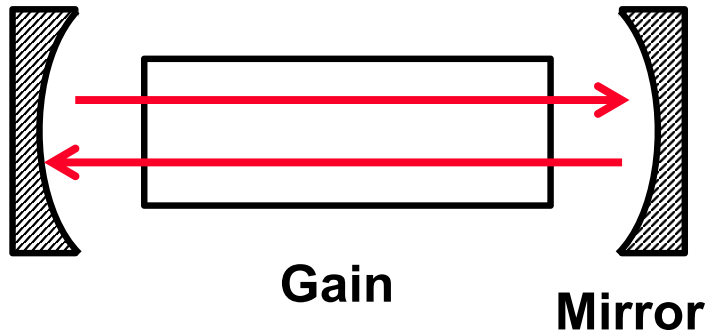
## **Lecture 2: Basic Concepts of Lasers**

**Instructor: Ming C. Wu**

**University of California, Berkeley**  
**Electrical Engineering and Computer Sciences Dept.**



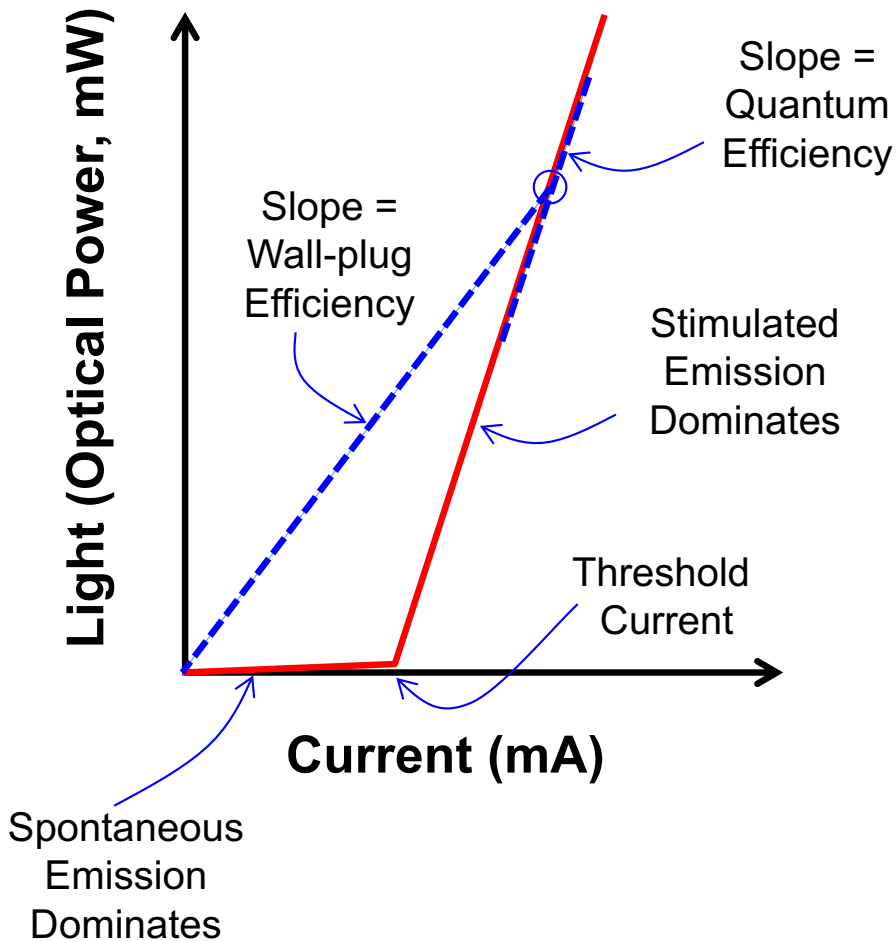
# Basic Concept of Lasers



- **Laser:**
  - Light **A**mplification by **S**timulated **E**mission of **R**adiation
- **Basic elements:**
  - Gain media
  - Optical cavity
- **Threshold condition:**
  - Bias point where laser starts to “lase”
  - Gain (nearly) equals loss



# L-I Curve of Semiconductor Lasers



- **Distinctive threshold (at least in classical lasers)**
- **Semiconductor laser is a forward-biased p-n junction, so mainly a current-biased device**
- **Threshold current :**
  - **Minimum current at which the laser starts to “lase”**
- **Quantum efficiency**
  - **“Differential” electrical-to-optical conversion efficiency, i.e., how many photons generated by injected electrons beyond threshold**
- **Wall-plug efficiency**
  - **Total electrical-to-optical conversion efficiency**



# “Edge-Emitting” Semiconductor Lasers

$g$  : gain coefficient [ $\text{cm}^{-1}$ ]

Light amplification:  $I(z) = I_0 e^{\Gamma g z}$

$\Gamma$ : confinement factor

(fraction of energy in gain media)

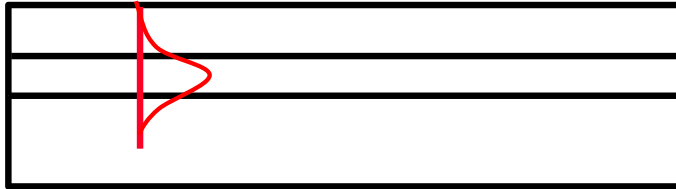
Threshold condition:

Round-trip gain = 1

$$e^{\Gamma g L - \alpha_i L} R_1 e^{\Gamma g L - \alpha_i L} R_2 = 1$$

$$g = g_{th} = \frac{\alpha_i}{\Gamma} + \frac{1}{2\Gamma L} \ln \left( \frac{1}{R_1 R_2} \right) = \frac{\alpha_i + \alpha_m}{\Gamma}$$

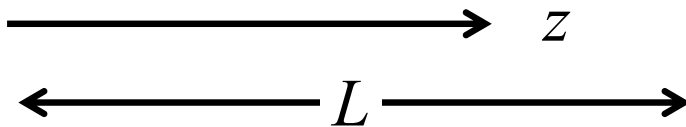
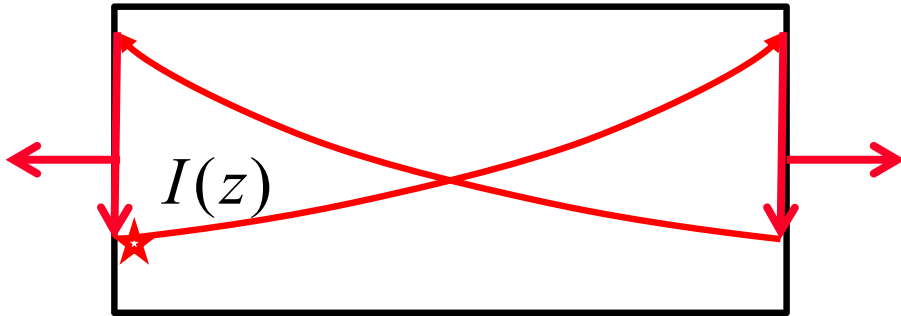
$$\begin{cases} \alpha_i : \text{intrinsic loss} \\ \alpha_m = \frac{1}{2L} \ln \left( \frac{1}{R_1 R_2} \right) : \text{mirror loss} \\ \text{(i.e., output light)} \end{cases}$$



**Semiconductor Laser**

**Cleaved Facet**

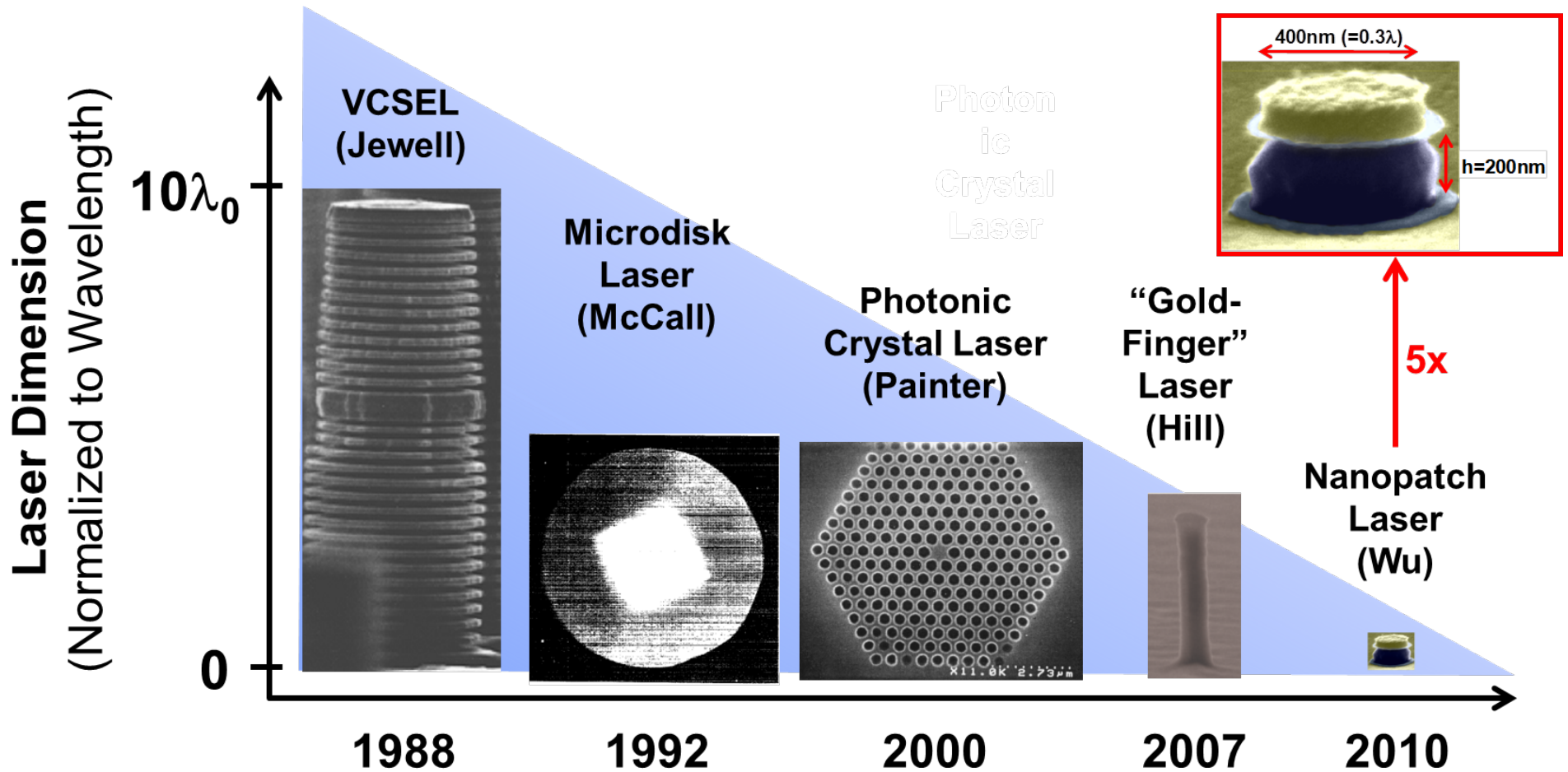
$$R = \left( \frac{n-1}{n+1} \right)^2, \quad R \sim 30\% \text{ for } n = 3.5$$





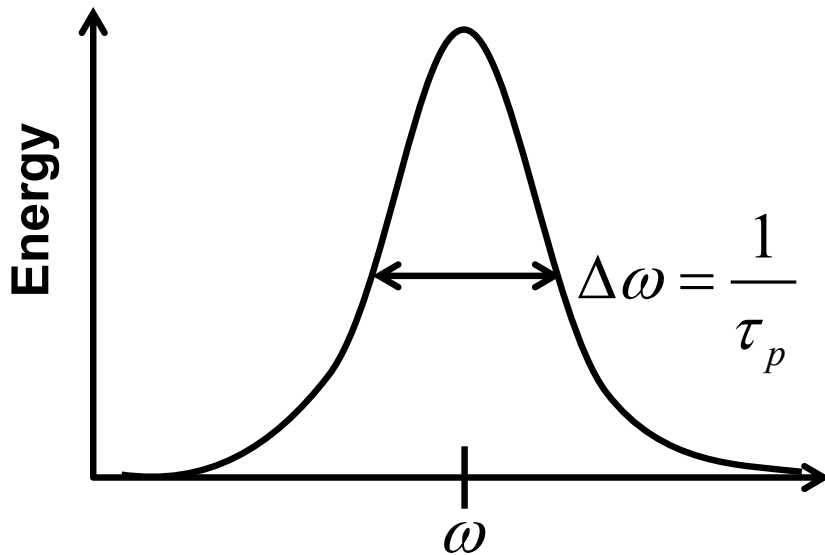
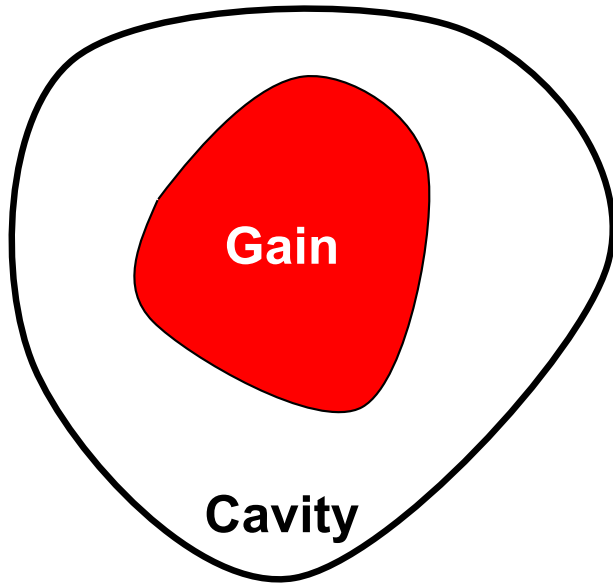
# Modern Lasers

- Optical cavity does not necessarily consist of mirrors





# Generic Description of Optical Cavity



Quality Factor:

$$Q = \frac{\text{Energy Stored}}{\text{Energy Dissipated per Cycle}}$$

$$Q = \frac{\omega}{\Delta\omega}$$

$$\Delta\omega = \frac{1}{\tau_p}$$

$\tau_p$  : photon lifetime [sec]

$$\frac{1}{\tau_p} = \alpha \frac{c}{n} \quad \left( \begin{array}{l} \alpha: \text{loss rate per cm} \\ 1/\tau_p: \text{loss rate per sec} \end{array} \right)$$

$$Q = \omega\tau_p$$



# Photon Lifetime and Spectral Width

Decay of optical energy when input is turned off  
(ring-down measurement):

$$I(t) = I_0 e^{-t/\tau_p} \quad \text{for } t \geq 0$$

Electrical (optical) field:

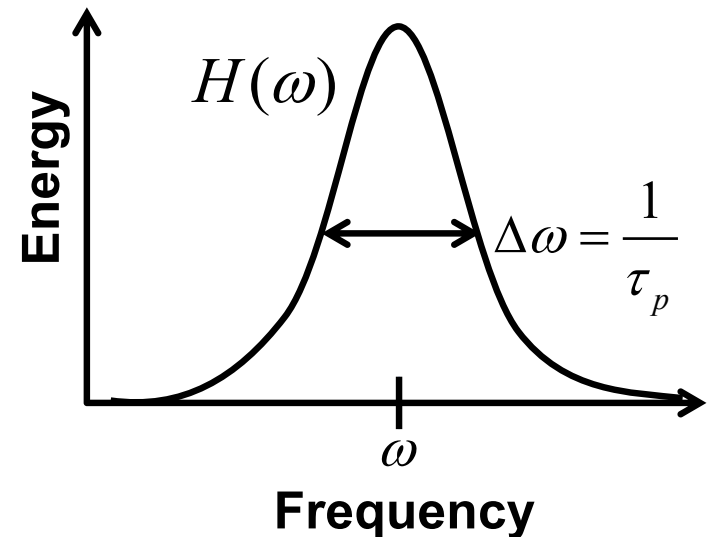
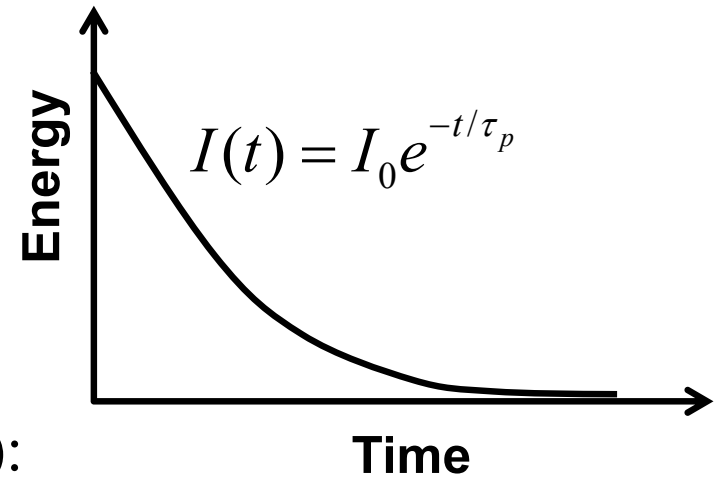
$$E(t) = E_0 e^{j\omega_0 t} e^{-t/2\tau_p} \quad \text{for } t \geq 0$$

Frequency domain response (Fourier transform):

$$H(\omega) = \int_0^{\infty} e^{j\omega_0 t} e^{-t/2\tau_p} e^{-j\omega t} dt = \frac{1}{j(\omega - \omega_0) + 1/2\tau_p}$$

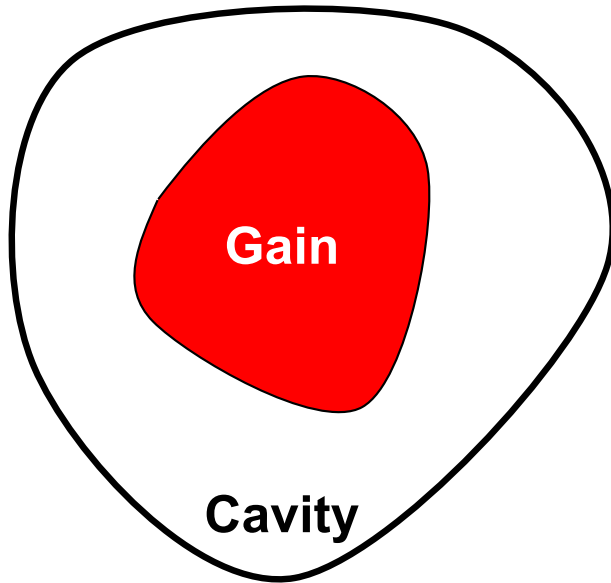
$$\text{FWHM of } |H(\omega)|^2 : \quad \omega - \omega_0 = \pm \frac{1}{2\tau_p}$$

$$\Delta\omega = \frac{1}{\tau_p}$$





# Threshold Condition of Generic Lasers

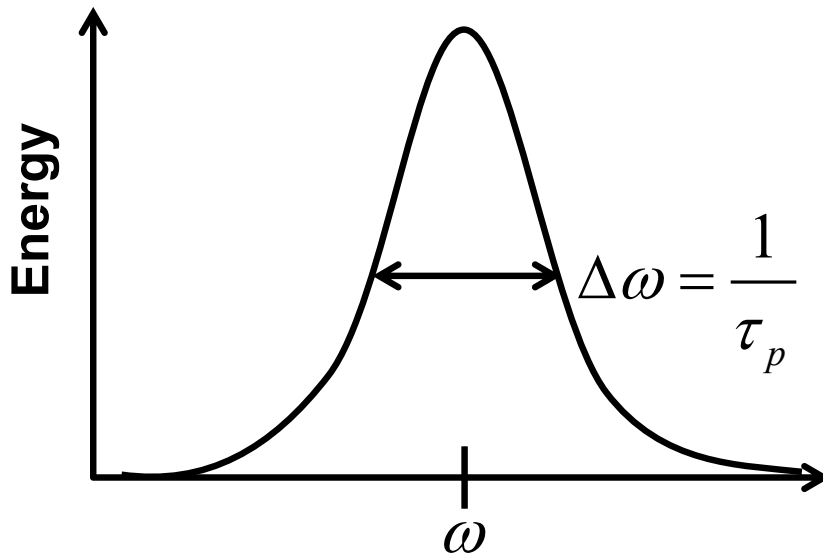


Gain = Loss

(rate of gain = rate of loss)

$$\Gamma g_{th} \frac{c}{n} = \frac{1}{\tau_p} = \frac{\omega}{Q}$$

$$g_{th} = \frac{\omega n}{Q \Gamma c}$$



Quantum efficiency:

$$\eta = \frac{\alpha_m}{\alpha_m + \alpha_i} = \frac{Q_{rad}^{-1}}{Q_{rad}^{-1} + Q_{loss}^{-1}} = \frac{Q_{rad}^{-1}}{Q^{-1}}$$

$$\eta = \frac{Q}{Q_{rad}}$$





# Typical Q of Semiconductor Laser

Edge-emitting laser:

$$L = 100\mu m, R = 30\%, \omega \sim 100\text{THz}, \tau_p \sim 1\text{ps}, Q \sim 600$$

Vertical Cavity Surface-Emitting Laser (VCSEL)

$$L = 1\mu m, R = 99\%, Q \sim 700$$

Microdisk (Whispering Gallery Mode or WGM) Laser

$$Q \sim 1000 \text{ (up to } 10^{11} \text{ possible in low loss materials)}$$

Photonic crystal laser:  $Q \sim 1000$  (up to  $10^6$  possible)

Metal cavity laser (plasmonic laser):  $Q \sim 10$  to 100



# Gain Cross-Section

Gain cross-section (instead of gain coefficient) is often used to measure the gain in gas or solid-state lasers:

$$\sigma : [\text{cm}^2]$$

Gain cross-section is related to gain by:

$$g = N\sigma$$

where  $N$  is concentration of active molecules

For comparison, in semiconductor lasers:

$$g \sim 100 \text{ cm}^{-1}$$

$$N \sim 10^{18} \text{ cm}^{-3} \quad (\text{typical electron concentration at threshold})$$

$$\sigma \sim 10^{-16} \text{ cm}^2 \quad (= (0.1 \text{ nm})^2)$$

Note: more precise relation between gain and carrier concentration will be discussed in future lectures